

## Homework 4 Fall 2018 TA: Robert Buckley

### Problem 1:

For the 248 nm UV machine, the total amount of wafers that can be made in a year:

$$N_w = 80 * 24 * 365 * \frac{4}{10} = 280,320 \text{ wafers}$$

$$\text{Cost per wafer: } C_w = \frac{10M}{N_w} = \$35.67$$

$$\text{Number of chips per wafer: } N_c = \frac{A_w}{A_{chip}} = 1413$$

$$\text{Cost per chip: } C_c = \frac{35.67}{1413} = \$0.025$$

For the 193nm UV machine:

$$\text{Wafers per year: } N_{w2} = 70080$$

$$\text{Cost per wafer: } C_{w2} = \$570.78$$

$$\text{Chips per wafer: } N_{c2} = 4580$$

$$\text{Cost per chip: } C_{c2} = \$0.125$$

$$\text{Cost difference } C_\Delta = 0.125 - 0.025 = \$0.1/\text{chip}$$

### Problem 2:

The dielectric constant of  $\text{SiO}_2 = K_s = 3.9$

The dielectric constant of  $\text{HfO}_2 = K_H = 25$

$$\rightarrow \text{Thickness of HfO}_2: t_{\text{HfO}_2} = \frac{25}{3.9} * t_{\text{SiO}_2} = 12.82 \text{ nm}$$

### Problem 3:

$$\text{The total volume of the oxide } V_{ox} = 10 \text{ nm} * 25 \text{ nm} * 2.5 \text{ nm} = 625 \text{ nm}^3$$

$$\text{The volume of one } \text{SiO}_2 \text{ molecule } V_{\text{SiO}_2} = 0.044 \text{ nm}^3$$

$$\text{Number of } \text{SiO}_2 \text{ molecules per gate } N_m = \frac{V_{ox}}{V_{\text{SiO}_2}} = 14204 \text{ molecules}$$

### Problem 4:

Resistivity of Aluminum  $2.8 * 10^{-8} \Omega * m$

$$\text{Resistance of the interconnect: } R = \frac{2.8 * 10^{-8} \Omega m}{80 * 10^{-9} m} * \frac{400 * 10^{-6} m}{60 * 10^{-9} m} = 2333.33 \Omega$$

### Problem 5:

The lowest resistance metal for interconnection is silver. It is often not used because silver is very expensive, and because when using silver there are electro migration issues during fabrication.

Problem 6:

The average thickness of a 12 inch (300 mm) wafer is 750-800  $\mu m$  With a 150  $\mu m$  saw the thickness per cut is 870-920  $\mu m$ .

$$A \text{ 2 meter pull can create } N_w = \frac{2m}{900 \cdot 10^{-6}m} \sim \frac{2m}{950 \cdot 10^{-6}m} = 2105 \sim 2222 \text{ wafers}$$

Problem 7:

From the last page we find,

$$\text{Poly1 sheet resistance} = 7.7 \frac{\Omega}{\square}$$

$$\text{poly1-Insulator-M1 capacitance} = 64 \frac{aF}{\mu m^2}$$

$$\omega_{3dB} = \frac{1}{RC} = 2\pi f \rightarrow R = \frac{1}{2\pi f \cdot C} = 19.89 \cdot 10^6 \Omega$$

a. The minimum area of a poly1 resistor is

$$A_{Resistor} = \frac{19.89 \cdot 10^6}{7.7} \cdot 0.2^2 \mu m^2 = 103.32 \cdot 10^3 \mu m^2$$

The minimum area of a Poly1-Poly2 ( $864 \frac{aF}{\mu m^2}$ ) capacitor is

$$A_{Capacitor} = \frac{10pF}{64 \frac{aF}{\mu m^2}} = 156.25 \cdot 10^3 \mu m^2$$

$$\text{Total Area } A = A_{Res} + A_{Cap} = 103.32 \cdot 10^3 + 156.25 \cdot 10^3 = 159.57 \cdot 10^3 \mu m^2$$

b) We will start with the minimized size resistor has a sheet of  $x \square$  and the capacitor has an area of  $y \mu m^2$ .

$$\text{Total area } A = (0.2 \cdot 0.2) \cdot x + y = 0.04x + y$$

$$\frac{1}{RC} = \omega_{3dB} = 2\pi f \rightarrow RC = \frac{1}{2\pi f} = 0.0001592 \text{ Hz}$$

$$(x \cdot 7.7)(65 \cdot 10^{-18} \cdot y) = 0.0001592 \rightarrow y = \frac{7.952 \cdot 10^{12}}{x}$$

$$A = 0.04x + \left( \frac{7.952 \cdot 10^{12}}{x} \right) \rightarrow A_{min} \text{ when } 0.04x = \frac{7.952 \cdot 10^{12}}{x}$$

$$x = 7.0495 \cdot 10^6 \rightarrow y = \frac{7.952 \cdot 10^{12}}{7.0495 \cdot 10^6} = 1.128 \cdot 10^6 \mu m^2$$

$$R = 7.0495 \cdot 10^6 \cdot 7.7 = 55.2 \cdot 10^6 = 54.2 \text{ M}\Omega$$

$$C = 1.128 \cdot 10^6 \cdot 64 \cdot 10^{-18} = 7.22 \cdot 10^{-11} = 72.2 \text{ pF}$$

#### Problem 8:

- a. Length =  $1\mu m$ , width =  $2\mu m$
- b. Positive photoresist underexposed decreases the size.  
Length =  $1 - 0.1 + (-0.1) = 0.8\mu m$   
Width is unchanged.
- c. Underexposing negative photoresist decreases the size  
Length =  $1 - 0.1 + 0.1 = 1.0\mu m$

#### Problem 9

Resistivity of Aluminum  $2.8 * 10^{-8} \Omega * m$

$$\text{Resistance of the interconnect } R_{Al} = \frac{\rho l}{wt} \rightarrow t = \frac{\rho l}{wR} = \frac{2.8 * 10^{-8} * 250 * 10^{-6}}{3 * 10^{-6} * 25} = 93.3 * 10^{-9} m = 93.3 nm$$

$$\text{Sheet resistance} = \frac{\rho}{t} = \frac{2.8 * 10^{-8}}{93.3 * 10^{-9}} = 0.3 \Omega/\blacksquare$$

#### Problem 10

Resistivity of Copper  $1.68 * 10^{-8} \Omega * m$

$$R_{Al} = \frac{\rho l}{wt} \rightarrow l = \frac{Rwt}{\rho} = \frac{2 * 10^{-6} * 25 * 93.3 * 10^{-9}}{1.68 * 10^{-8}} = 11.107 * 10^{-6} = 11.107 \mu m$$

#### Problem 11

Approximately 53% of the oxide grows above the wafer, and 47% grows into the wafer.

$$\text{The increased wafer height } W_{height} = 0.53 * 5000 = 2650 \text{ \AA}$$

#### Problem 12

Poly 1:  $7.7 \Omega/\blacksquare$

P+:  $7.5 \Omega/\blacksquare$

For 10k Ohms

$$\text{Poly1: } \frac{5,000}{7.7} = 649.4 \blacksquare's$$

$$\text{P+: } \frac{5,000}{7.5} = 666.7 \blacksquare's$$

There are a lot of different ways to create the serpentine layout, depending on how many rows you want to make, but it will take approximately 2.3x the area for the P+ resistor. The main reason for this is that a P+  $\blacksquare$  is  $0.3 \times 0.3$  microns while a Poly  $\blacksquare$  is  $0.2 \times 0.2$  microns

## Problem 13-14

### Code

```
1  module NOR2 (i_A, i_B, o_F);
2      input i_A, i_B;
3      output o_F;
4
5      assign o_F = ~(i_A||i_B);
6
7  endmodule

```

```
1  module AND2 (i_A, i_B, o_F);
2      input i_A, i_B;
3      output o_F;
4      wire A_not, B_not;
5
6      NOR2 nor0(.i_A(i_A), .i_B(i_A), .o_F(A_not));
7      NOR2 nor1(.i_A(i_B), .i_B(i_B), .o_F(B_not));
8      NOR2 nor2(.i_A(A_not), .i_B(B_not), .o_F(o_F));
9
10 endmodule

```

```
module OR2 (i_A, i_B, o_F);
    input i_A, i_B;
    output o_F;
    wire A_nor_B;

    NOR2 nor0(.i_A(i_A), .i_B(i_B), .o_F(A_nor_B));
    NOR2 nor1(.i_A(A_nor_B), .i_B(A_nor_B), .o_F(o_F));

endmodule

```

---

```
module Mux_2_1 (i_A, i_B, i_S, o_F);
    input [1:0] i_A, i_B;
    input i_S;
    output [1:0] o_F;
    wire [1:0] AS, BS;
    wire w_Sn;

    NOR2 nor0(.i_A(i_S), .i_B(i_S), .o_F(w_Sn));
    AND2 and0(.i_A(i_A[1]), .i_B(i_S), .o_F(AS[1]));
    AND2 and1(.i_A(i_A[0]), .i_B(i_S), .o_F(AS[0]));
    AND2 and2(.i_A(i_B[1]), .i_B(w_Sn), .o_F(BS[1]));
    AND2 and3(.i_A(i_B[0]), .i_B(w_Sn), .o_F(BS[0]));
    OR2 or0 (.i_A(AS[0]), .i_B(BS[0]), .o_F(o_F[0]));
    OR2 or1 (.i_A(AS[1]), .i_B(BS[1]), .o_F(o_F[1]));

endmodule

```

```

module Inverter4 (i_A,o_F);
    input  [3:0] i_A;
    output [3:0] o_F;

    NOR2 nor0(.i_A(i_A[0]), .i_B(i_A[0]), .o_F(o_F[0]));
    NOR2 nor1(.i_A(i_A[1]), .i_B(i_A[1]), .o_F(o_F[1]));
    NOR2 nor2(.i_A(i_A[2]), .i_B(i_A[2]), .o_F(o_F[2]));
    NOR2 nor3(.i_A(i_A[3]), .i_B(i_A[3]), .o_F(o_F[3]));

endmodule

module Mux4_2_1 (i_A, i_B, i_S, o_F);
    input [3:0] i_A, i_B;
    input i_S;
    output [3:0] o_F;

    Mux_2_1 mux0(.i_A(i_A[1:0]), .i_B(i_B[1:0]), .i_S, .o_F(o_F[1:0]));
    Mux_2_1 mux1(.i_A(i_A[3:2]), .i_B(i_B[3:2]), .i_S, .o_F(o_F[3:2]));

endmodule

```

Testbench:

```

module HW4_Problem();
    reg [3:0] r_A;
    reg r_S;
    wire [3:0] w_An, w_F;

    initial
    begin
        r_A = 4'b0000;
        r_S = 1'b0;
    end

    always
        #10 r_S = ~r_S;
    always
        #20 r_A = r_A+1;

    Inverter4 inv0(.i_A(r_A), .o_F(w_An));
    Mux4_2_1 mux0(.i_A(w_An), .i_B(r_A), .i_S(r_S), .o_F(w_F));

endmodule

```

Output:

r_A	0	0	1	2	3	4	5	6	7	8	9
w_An	15	14	13	12	11	10	9	8	7	6	5
r_S	0	1	0	1	0	1	0	1	0	1	0
w_F	0	15	1	14	2	13	3	12	4	11	5